

	Class	Subclass
ISSUE CLASSIFICATION		

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

O.I.P.E.

SCANNED AC4 Q.A. AA

APPLICATION NO. 09/964480	CONT/PRIOR F	CLASS 324	SUBCLASS 15	ART UNIT 2858 3929	EXAMINER P. Patel
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APPLICANTS

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title

Semiconductor integrated circuit testing system and method

PTO-2040
12/89

ISSUING CLASSIFICATION

[illegible]

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
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